Test Probe INGUN E-Type

E-075 214 064 A 2000

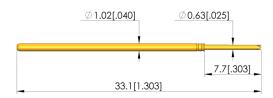
Item E-075-0033





- Highest contact reliability under challenging test conditions without additional stress on the DUT: up to 25% larger contact surface between test probe and DUT
- When hitting the test surface a spring force up to 100% higher than a standard GKS is available, but the same spring force as a standard GKS is achieved at the working stroke.







General data

Product group: ICT / FCT (in-circuit test and function test Sub-product group: INGUN E-TYPE® Series: E-075 Grid: 1.91 mm [75.1 mil] Contacting from: Pad Magnetic: Yes Installation type: Plug-in Quick-exchange system: Yes Adjustable installation height: No Non-rotating: No Compatible receptacle(s): KS-075 Min. temperature: -40 °C [-40 °F] Max. temperature: 80 °C [176 °F] RoHS-compliant:

Tip style data

Tip Style data	
Tip style:	14 4-point crown, self-cleaning
Tip diameter:	0.64 mm [.025 in]
Tip style surface:	A gold
Tip style material:	2 steel

Electrical data

Current load capacity / rated current: ЗА Typical resistance (Ri): 20 mOhm

Mechanical data

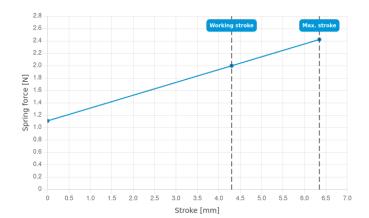
Total length:	33.1 mm [1.3 in]
Barrel diameter:	1.02 mm [.04 in]
Maximum stroke:	6.35 mm [.25 in]
Spring pre-load:	1.11 N [3.99 ozf]
Collar height:	00
Spring force at working stroke:	2 N [7.19 ozf]
Recommended working stroke:	4.3 mm [.169 in]

Partner for Future Technology

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ICT/FCT Test probes



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